


**FORM PTO-1449**

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Applicant: Robert G. Messerschmidt, et al		
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DEPARTMENT OF PATENTS AND PUBLICATIONS FOR  
 APPLICANT'S INFORMATION  
 DISCLOSURE STATEMENT

### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
AA	5,596,992	01/28/97	Haaland et al	128	664	
AB	5,945,674	08/31/99	Dukor	250	339.11	
AC	6,421,548 B1	07/16/02	Berman et al	600	322	
AD	10/262,692		Jones			10/02/02

### FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
			<i>None</i>			

### OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

CS	<i>NY</i>	The Continual Evolution of the Pap Smear, OB/GYN special edition, vol. 5, 2002, pp 61-64				
CT	<i>NY</i>	Skoog, D. A. and Leary, J. J., "Principles of Instrumental Analysis", Fort Worth: Saunders, 1992, pp 123-149				
CU	<i>NY</i>	Fahrenfort, J., "Attenuated Total Reflection - A new principle for the production of useful infra-red reflection spectra of organic compounds" Spectrochimica Acta, (1961) vol. 17, pp. 608-700. Pergamon Press Ltd.				
CV		<del>Harriek, N.J., "Internal Reflection Spectroscopy", Interscience Publishers, Copyright 1967 by John Wiley &amp; Sons, Inc. Library of Congress Catalog Number 67-13944.</del>				
CW	<i>NY</i>	Fringeli, U. P.; Goette, Jeannette; Reiter, Gerald; Siam, Monira; Baurecht, Dieter; "Structural Investigations of Oriented Membrane Assemblies by FTIR-ATR Spectroscopy," Institute of Physical Chemistry, University of Vienna, Althanstrasse 14, A-1090 Vienna, Austria. Medinova AG, Eggbühlstrasse 14, CH-8050 Zurich, Switzerland. DeHaseth, J.A., AIP Conference Proceedings No. 430, 1998, The American Institute of Physics, Woodbury, N.Y.				
CX	<i>NY</i>	Haaland, D. M.; Jones, H. D. T.; Thomas, E. V., "Multivariate Classification of Infrared Spectra of Cell and Tissue Samples," Applied Spectroscopy, Vol. 51, Number 3, 1997, pp. 340-345.				
CY	<i>NY</i>	Levenson, R. M.; Hoyt, C. C., "Spectral Imaging and Microscopy," American Laboratory, 2000, pp. 1-8.				

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.